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# Crystal structures of ErGe<sub>2</sub> and TmGe<sub>2</sub> compounds

#### Abstract

Crystal structures of  $ErGe_2$  and  $TmGe_2$  compounds were determined by X-ray single crystal diffraction. Both  $TmGe_2$  and  $ErGe_2$  crystallized with the  $ZrSi_2$  structure type (space group *Cmcm*).

Keywords: Rare earths phases, Crystal structure, X-Ray diffraction

#### Introduction

This paper is a part of systematic study of interaction of erbium and thulium with germanium. Previously, such compounds containing rare earth metals ~33.3 at.% have been investigated: YGe<sub>2</sub> (space group  $I4_1/amd$ , structure type ThSi<sub>2</sub>)<sup>1</sup> LaGe<sub>2</sub> (space group  $I4_1/amd$ , structure type ThSi<sub>2</sub>)<sup>2</sup>, CeGe<sub>2</sub> (space group  $I4_1/amd$ , structure type ThSi<sub>2</sub>)<sup>3</sup>, PrGe<sub>2</sub> (space group  $I4_1/amd$ , structure type ThSi<sub>2</sub>)<sup>4</sup>, NdGe<sub>2</sub> (space group  $I4_1/amd$ , structure type ThSi<sub>2</sub>)<sup>5</sup>, SmGe<sub>2</sub> (space group  $I4_1/amd$ , structure type ThSi<sub>2</sub>)<sup>6</sup>, EuGe<sub>2</sub> (space group P-3m1, structure type EuGe<sub>2</sub>)<sup>7</sup>, TbGe<sub>2</sub>(space group Cmmm)<sup>8</sup>, TmGe<sub>1.891</sub>, ErGe<sub>1.891</sub> (space group Pmma)<sup>9</sup>. In this paper, we report our results on synthesis and crystal structure refinement of the ErGe<sub>2</sub> and TmGe<sub>2</sub> binary compounds by X-ray single crystal diffraction.

#### **Experimental details and results**

The samples were melted from weighted pieces of initial components of high purity (Er - 99.86%, Tm - 99.89%, Ge - 99.999%) under an argon Tigettered atmosphere in an arc furnace with a water-cooled copper hearth and then annealed in an evacuated silica tubes at 873 K for one month.

The samples microstructures were studied using a metallographic microscope (magnification  $\times 200 \div 300$ ). The elemental compositions of some samples were confirmed using the registering scanning electron microscope REM-MA-102-02 type with 1µm<sup>2</sup> locality of analysis (Fig.1 and Fig.2).



Fig. 1. SEM image for the  $Er_{34}Ge_{66}$  (composition of main phase Er(32.998), Ge(67.002))



**Fig. 2.** SEM image for the  $Tm_{34}Ge_{66}$  (composition of main phase Tm(35,359), Ge(64,641))

X-ray patterns of all alloys were taken at room temperature using X-ray powder diffractometer DRON-2.0M with Fe  $K_{\alpha}$  radiation ( $\theta/2\theta$  scanning,  $30^{\circ} \le 2\theta \le 150^{\circ}$ ) and the pure silicon as an internal standard.

The single crystals suitable for X-ray analysis were first checked using Laue and Weissenberg methods (RKV-86 and RGNS-2 chambers,  $MoK\alpha$ -

radiation), and afterwards they were studied using automatic single-crystal diffractometer Bruker APEX II (MoK $\alpha$ -radiation, graphite monochromator,  $\omega$ scans).

## **Results and discussion**

The single crystals of  $ErGe_2$  and  $TmGe_2$  having prismatic forms were extracted from the samples with the compositions  $Er_{34}Ge_{66}$  and  $Tm_{34}Ge_{66}$ , respectively. Processing of collection and reduction data were performed using SAINT (Bruker, 2004) programs<sup>10</sup>. The solution and refinement of crystal structure were performed using SHELXL-97 programme package<sup>11</sup>. Standardization procedure was performed using program Structure Tidy<sup>12</sup>.

These single crystals were stable in air over the long period of time and had metallic luster. The details of data collection and structure refinement, atomic coordinates and anisotropic thermal displacement parameters for  $ErGe_2$  are given in Table 1. The same data for  $TmGe_2$  are listed in Table 2.

Tabl	e 1	. Ext	perimental	details	and	crv	stall	ogra	phic	data	for	ErG	e2
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Compound			ErGe <sub>2</sub>				
Structure type			ZrSi <sub>2</sub>				
Space group			Cmcm				
Pearson symbo	1		oC12				
Lattice parame	ters, Å		a = 4.0190(1), b = 15.8381(7), c = 3.8799(1)				
Absorption coe	fficient, mm <sup>-1</sup>		57.436				
Theta range for	data collection		2.4 to 28.0°				
Limiting indice	s		-5 =< h =< 4, -19 =< k =< 19, -4 =< 1 =< 3				
Reflections col	lected / unique		168/152				
Refinement me	thod		Full-matrix least-squares on F <sup>2</sup>				
Data / restraint	s / parameters		152/0/14				
Goodness-of-fi	t on $F^2$		1.102				
Final R indices	[I>2sigma(I)]		R1 = 0.0321, wR2 = 0.0956				
R indices (all d	ata)		R1 = 0.0389, $wR2 = 0.1004$				
Extinction coef	ficient		0.0008(7)				
Largest diff. pe	ak and hole		1.270 and -1.124 e <sup>.</sup> Å <sup>-3</sup>				
Atomic coordin	nates and displacem	ents: x y	$z, U_{11}, U_{22}, U_{33} U_{23} U_{13} U_{12}(\text{\AA}^2)$				
Er1 (4c)	0.00000 0.39620	1/4	0.01301 0.01192 0.00943 0.00000				
			0.00000 0.00000				
Ge1 (4c)	-0.50000 $0.44545$	-1/4	0.01304 0.02073 0.00911 0.00000				
			0.00000 0.00000				
Ge2 (4c)	0.00000 0.24760	-1/4	0.01616 0.01259 0.01322 0.00000				
			0.00000 0.00000				

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Table 2. Experimental details and crystallographic data for TmGe<sub>2</sub>

Compound			TmGe <sub>2</sub>				
Structure type			ZrSi <sub>2</sub>				
Space group			Cmcm				
Pearson symbol			oC12				
Lattice parameters	s, Å		a = 4.020(1), b = 15.768(4), c = 3.8761(5)				
Absorption coeffic	cient, mm <sup>-1</sup>		59.704				
Theta range for da	ata collection		5.10 to 27.00°				
Limiting indices			-3 =< h =< 5, -15 =< k =< 19, -4 =< 1 =< 4				
Reflections collec	ted / unique		162/1468				
Refinement metho	od		Full-matrix least-squares on F <sup>2</sup>				
Data / restraints /	parameters		162/0/15				
Goodness-of-fit of	$n F^2$		1.112				
Final R indices [I:	>2sigma(I)]		R1 = 0.0307, wR2 = 0.0877				
R indices (all data	l)		R1 = 0.0354  wR2 = 0.0913				
Largest diff. peak	and hole		1.043 and -1.222 e <sup>-</sup> Å <sup>-3</sup>				
Atomic coordinate	es and displacements	: x y	$v_{2}$ , $U_{11}$ , $U_{22}$ , $U_{33}$ $U_{23}$ $U_{13}$ $U_{12}(\text{\AA}^2)$				
Tm1 (4c)	0.00000 0.39650	1/4	0.01339 0.01752 0.01210 0.00000				
			0.00000 0.00000				
Ge1 (4c)	-0.50000 0.55284	-1/4	0.01257 0.02851 0.01015 0.00000				
			0.00000 0.00000				
Ge2 (4c)	-0.50000 0.25249	-1/4	0.01729 0.01832 0.01409 0.00000				
			0.00000 0.00000				

The  $\text{ErGe}_2$  and  $\text{TmGe}_2$  compounds crystallize in the  $\text{ZrSi}_2$  structure type (space group *Cmcm*, Pearson code *oP*12). Both structures were also confirmed by powder diffraction methods. The unit cell projection and packing of trigonal prism in the TmGe<sub>2</sub> structure are shown Fig. 3.



Fig. 3. The unit cell projection and packing of trigonal prism in the TmGe<sub>2</sub> structure

A paper concerning the Tm-Ge binary phases has recently been published<sup>9</sup> and reported on powder X-ray investigation of binary thulium germanides. Three new compounds have been characterized, TmGe<sub>1.83</sub> with the ErGe<sub>1.83</sub>-type structure (Cmcm; a=4.050(1) Å, b=29.460(8) Å and c=3.887(1) Å), Tm<sub>2</sub>Ge<sub>5</sub> with the Er<sub>2</sub>Ge<sub>5</sub>-type structure (Pmmn: a=4.000(1) Å; b=3.875(1) Å; c=18.103(7) Å) and TmGe<sub>1.9</sub> with a new structural type (Pmma; a=3.879(1) Å, b=4.034(1) Å and c=22.544(7) Å). The structure of TmGe<sub>1.9</sub> has been solved by powder X-ray diffraction. This new type may be considered as an intergrowth of ZrSi<sub>2</sub> and ErGe<sub>1.83</sub> blocks. This intergrowth structure at the TmGe<sub>2</sub> composition has not been observed.

### Conclusions

- 1. The crystal structures of the ErGe<sub>2</sub> and TmGe<sub>2</sub> compounds were determined by X-ray single crystal diffraction.
- 2. Both compounds crystallized in the ZrSi<sub>2</sub> structure type (space group *Cmcm*, Pearson code *oP*12).
- 3. The intergrowth of  $ZrSi_2$  and  $ErGe_{1.83}$  blocks in the  $TmGe_2$  crystal were not observed.

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